

IGBT

TRENCHSTOP™ IGBT4 High Power Chip IGC99T120T8RH

Data Sheet

Industrial Power Control



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TRENCHSTOP[™] IGBT4 High Power Chip

Features:

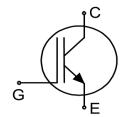
- 1200V trench & field stop technology
- Low V_{CEsat}
- Soft turn off
- Positive temperature coefficient
- Easy paralleling

Recommended for:

Medium / high power modules

Applications:

• Medium / high power drives



Chip Type	V _{CE}	I Cn	Die Size	Package
IGC99T120T8RH	1200V	100A	9.5mm x 10.39mm	Sawn on foil

Mechanical Parameters

Die size		9.5 x 10.39		
Emitter pad size		See chip drawing	mm^2	
Gate pad size		1.31 x 0.811		
Area total		98.71		
Silicon thickness		140	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	258		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		AI, ≤500μm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C		
(<6 months)	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Environment.		



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _{vj} =25°C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;\;1}$	I _C	-	А
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vjmax}^{\ \ 2}$	I _{C,puls}	300	А
Gate-emitter voltage	V_{GE}	±20	V
Virtual junction operating temperature	$T_{\rm vj}$	-40 +175	°C
Short circuit data $^{1/2/3}$ V_{GE} =15V, V_{CC} =800V, T_{vj} =150°C	t _{sc}	10	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol	Conditions	Value			Unit
raiailietei	Symbol	Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I_{C} =3.8mA	1200	ı	ı	
Collector-emitter saturation voltage	$V_{\sf CEsat}$	V _{GE} =15V, I _C =100A	1.48	1.70	1.92	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =3.8mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I _{CES}	$V_{\text{CE}} = 1200 \text{V}, \ V_{\text{GE}} = 0 \text{V}$	-	1	13	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$		ı	120	nA
Integrated gate resistor	r _G		-	7.5	-	Ω

Electrical Characteristics ²

Parameter	Symbol	Conditions	Value			Unit
raiametei	Syllibol	Conditions	min.	typ.	max.	Ollit
Collector-emitter saturation voltage	V _{CEsat}	V_{GE} =15V, I_{C} =100A, T_{vj} =150°C	-	2.1	-	V
Input capacitance	C _{ies}	V _{CE} =25V,	-	6300	-	n.E
Reverse transfer capacitance	C _{res}	V_{GE} =0V, f =1MHz T_{vj} =25°C	-	270	-	pF

¹ Depending on thermal properties of assembly.

² Not subject to production test - verified by design/characterization.

³ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

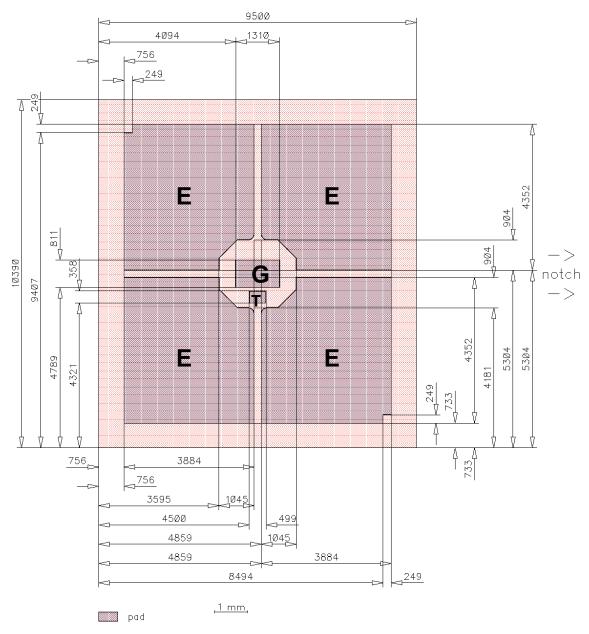
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FZ400R12KP4	Rev. 2.2
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Chip Drawing





E = Emitter

G = Gate

T = Test pad do not contact



Bare	Die	Prod	uct S	Spec	ifics
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Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description		
AQL 0.65 for	visual inspection according to failure catalogue	
Electrostatic I	Discharge Sensitive Device according to MIL-STD 883	
Revision His	tory	
Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	29.04.2016
Relevant Ap	plication Notes	



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